

IN THE CLAIMS:

No claims have been amended herein. All of the pending claims 1 through 3 are presented below. This listing of claims will replace all prior versions and listings of claims in the application. Please enter these claims as amended.

Listing of Claims:

1. (Previously presented) A testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing an enhanced reliability testing flag in the integrated circuit device associated with a
unique identification code of each integrated circuit device of the plurality of integrated
circuit devices for indicating whether each integrated circuit device requires enhanced
reliability testing;
automatically reading the unique identification code of each integrated circuit device of the
plurality of integrated circuit devices when each integrated circuit device of the plurality
of integrated circuit devices forms a portion of a wafer;
accessing the enhanced reliability testing flag stored for the unique identification code of each
integrated circuit device of the plurality of integrated circuit devices;
sorting the plurality of integrated circuit devices in accordance with whether their enhanced
reliability testing flag indicates they are in need of the enhanced reliability testing; and
performing the enhanced reliability testing for each integrated circuit device of the plurality of
integrated circuit devices requiring the enhanced reliability testing.

2. (Previously presented) A reliability testing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing a reliability testing flag in the integrated circuit device associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the reliability testing flag stored for each unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and
performing the further reliability testing for each integrated circuit device of the plurality of integrated circuit devices requiring the further reliability testing.

3. (Previously presented) A manufacturing method for an integrated circuit of an integrated circuit device of a plurality of integrated circuit devices comprising:
storing a reliability testing flag in the integrated circuit device associated with a unique identification code of each integrated circuit device of the plurality of integrated circuit devices for indicating whether each integrated circuit device requires further reliability testing;
automatically reading the unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
accessing the reliability testing flag stored for each unique identification code of each integrated circuit device of the plurality of integrated circuit devices;
sorting the plurality of integrated circuit devices in accordance with whether their reliability testing flag indicates they are in need of the further reliability testing; and
performing the further reliability testing for each integrated circuit device of the plurality of integrated circuit devices requiring the further reliability testing.